



FORM PTO/SB/08 (08-00) Substitute for form 1449:PTO		ATTY DOCKET NO. 8200.739		APPLICATION NO. 10/648,824 <i>10/648,804</i>	
US DEPT. OF COMMERCE PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) KIEHL			
		FILING DATE August 27, 2003		GROUP 1725	
U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS
<i>AC</i>		4,560,855	12/24/1985	TAKAFUJI et al.	<hr/> <hr/>
<i>↓</i>		4,881,430	11/21/1989	HUBBARD	<hr/> <hr/>
<i>↓</i>		5,318,213	6/7/1994	STRICKLAND et al.	<hr/> <hr/>
<i>AC</i>		US 2003/0038118 A1	2/27/2003	SUN et al.	<hr/> <hr/>
<i>AC</i>		US 2002/0166843 A1	11/14/2002	WANG et al.	<hr/> <hr/>
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FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUB CLASS
<i>AC</i>		EP 1 216 782 A2	6/26/2002	EUROPE	<hr/> <hr/>
<i>↓</i>		JP A 2003-71530 (with English-language Abstract)	3/11/2003	JAPAN	<hr/> <hr/>
<i>AC</i>		EP 1 201 345 A1	5/2/2002	EUROPE	<hr/> <hr/>
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)					
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EXAMINER <i>M. Alexandra Elve</i>				DATE CONSIDERED <i>9/3/05</i>	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					



FORM PTO/SB/08 (08-00) <small>Schedule for form 1449 PTO</small>		ATTY DOCKET NO. 8200.739	APPLICATION NO. 10648824 10648804			
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